Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/641,701	KIM, WOOK
Examiner	Art Unit
Jung Park	2616

	SEARCHED			
Class	Subclass	Date	Examiner	
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Subclass	Date	Examiner
	<u> </u>	Subclass Date

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
370/392, 395.1, 395.52, 351, 352, 389, 396-399, 401, 466	4/13/2007	JP
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